Substitute Disclosure Form (PTO-1449)

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademerk Office		Application No. 10/718,832
		Applicant	
(Use several st		Filling Date November 21, 2003	Group Art Unit 1763

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
11/	AA	5,843,847	12/01/1998	Pu et al.			
NW	AB	6,436,812	8/20/2002	Lee ,			
VIII	AC	2002 / 0132488	9/19/2002	Nallan			
1	AD			•		<del></del>	
-	AE						
	AF						
	AG						
-	AH						
	AI						<del> </del>

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Transl Yes	
ANL	AJ	61-171127	8/1/1986	Japan (English abstract only)				
	AK							
	AL							
	AM							
	AN							

	Other D	ocuments (include Author, Title, Date, and Place of Publication)
Examiner	Desig.	
Initial	ID	Document
11/2	AO	M. Oda et al. "Xray mask fabrication technology for". Journal of Vacuum Science & Technology B 14(6):4366-4370, Nov-Dec. 1996.
11/	AP	P. E. Riley et al. "Implementation of Tungsten Metallization In Multilevel Interconnection Technologies". IEEE Transactions on Semiconductor Manufacturing 3(4): 150-157, November 1990.
1	AQ	
	AR	

Examiner Signature	Date Considered				
LINCH	1/21/05				
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with					
next communication to applicant.					